

<b>Notice of References Cited</b>	Application/Control No. 10/825,426		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner DANIEL TSEGAYE		Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0158587	10-2002	Komiya, Naoaki	315/169.3
*	B	US-2006/0139251	06-2006	Morosawa et al.	345/076
*	C	US-6,731,273	05-2004	Koyama et al.	345/204
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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**NON-PATENT DOCUMENTS**

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